

AN78M00/AN78M00F Series

3-pin Positive Output Voltage Regulators (500mA Type)

Overview

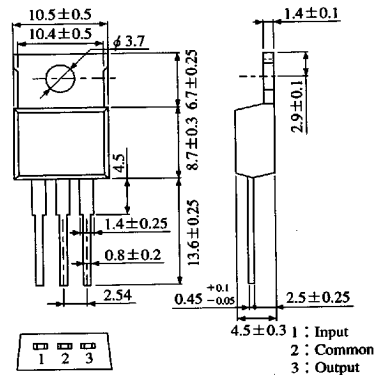
The AN78M00 and the AN78M00F series are 3-pin fixed positive output voltage regulators. Stabilized fixed output voltage is obtained from unstable DC input voltage without using any external components. 11 types of fixed output voltage are available ; 5V, 6V, 7V, 8V, 9V, 10V, 12V, 15V, 18V, 20V and 24V. They can be used widely in power circuits with current capacitance up to 500mA.

Features

- No external components
- Output voltage : 5V, 6V, 7V, 8V, 9V, 10V, 12V, 15V, 18V, 20V, 24V
- Short-circuit current limiting built-in
- Thermal overload protection built-in
- Output transistor safe area compensation

AN78M00 Series

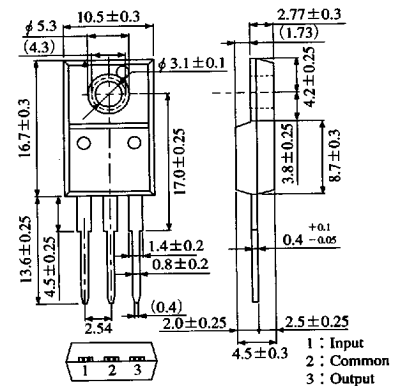
Unit : mm



JEDEC : TO-220AB (HSIP003-P-0000)

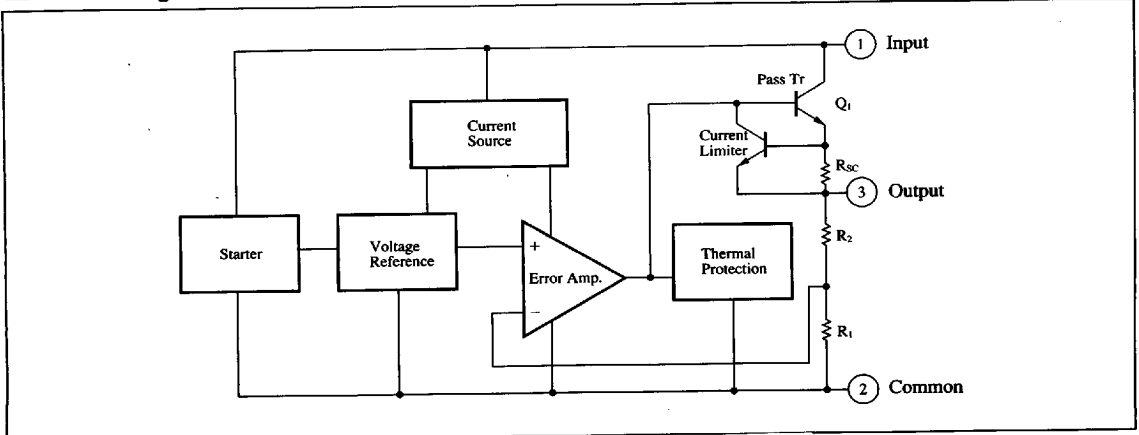
AN78M00F Series

Unit : mm



TO-220 Full Pack Package (HSIP003-P-0000A)

Block Diagram



6932852 0012527 366

Panasonic

■ Absolute Maximum Ratings (Ta=25℃)

Parameter		Symbol	Rating	Unit
Input voltage		V _I	35 *1	V
			40 *2	V
Power dissipation	AN7800 Series	P _D	15 *3	W
	AN7800F Series		10.25 *3	
Operating ambient temperature		T _{opr}	-20 to +80	℃
Storage temperature		T _{stg}	-55 to +150	℃

*1 AN78M05/F, AN78M06/F, AN78M07/F, AN78M08/F, AN78M09/F, AN78M10/F, AN78M12/F, AN78M15/F, AN78M18/F
*2 AN78M20/F, AN78M24/F
*3 Follow the derating curve. When T_J exceeds 150℃, the internal circuit cuts off the output.

■ Electrical Characteristics (Ta=25℃)

• AN78M05/AN78M05F (5V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V _O	T _J =25℃	4.8	5	5.2	V
Output voltage tolerance	V _O	V _I =7.5 to 20V, I _O =5 to 350mA, T _J =25℃, P _D ≤*	4.75	—	5.25	V
Line regulation	REG _{IN}	V _I =7.5 to 25V, T _J =25℃	—	3	100	mV
		V _I =8 to 25V, T _J =25℃	—	1	50	mV
Load regulation	REG _L	I _O =5 to 500mA, T _J =25℃	—	20	100	mV
		I _O =5 to 200mA, T _J =25℃	—	10	50	mV
Bias current	I _{bias}	T _J =25℃	—	4	6	mA
Input bias current fluctuation	ΔI _{bias} (IN)	V _I =8 to 25V, T _J =25℃	—	—	0.8	mA
Load bias current fluctuation	ΔI _{bias} (L)	I _O =5 to 350mA, T _J =25℃	—	—	0.5	mA
Output noise voltage	V _{no}	f=10Hz to 100kHz	—	40	—	μV
Ripple rejection ratio	RR	V _I =8 to 18V, I _O =100mA, f=120Hz	62	—	—	dB
Minimum input/output voltage difference	V _{DIF(min.)}	I _O =500mA, T _J =25℃	—	2	—	V
Output short circuit current	I _O (Short)	V _I =35V, T _J =25℃	—	300	—	mA
Peak output current	I _O (Peak)	T _J =25℃	—	700	—	mA
Output voltage temperature coefficient	ΔV _O /Ta	I _O =5mA, T _J =0 to 125℃	—	-0.5	—	mV/℃

Note 1) The specified condition T_J=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.
Note 2) When not specified, V_I=10V, I_O=350mA, C_I=0.33 μF and C_O=0.1 μF
* AN78M00 Series : 15W, AN78M00F Series : 10.25W

Voltage
Regu-
lators

■ Electrical Characteristics (Ta=25°C)

• AN78M06/AN78M06F (6V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_o	$T_j=25^\circ\text{C}$	5.75	6	6.25	V
Output voltage tolerance	V_o	$V_i=8.5$ to 21V , $I_o=5$ to 350mA , $T_j=25^\circ\text{C}$, $P_D \leq *$	5.7	—	6.3	V
Line regulation	REG_{IN}	$V_i=8.5$ to 25V , $T_j=25^\circ\text{C}$	—	5	100	mV
		$V_i=9$ to 25V , $T_j=25^\circ\text{C}$	—	1.5	50	mV
Load regulation	REG_{L}	$I_o=5$ to 500mA , $T_j=25^\circ\text{C}$	—	20	120	mV
		$I_o=5$ to 200mA , $T_j=25^\circ\text{C}$	—	10	60	mV
Bias current	I_{bias}	$T_j=25^\circ\text{C}$	—	4	6	mA
Input bias current fluctuation	$\Delta I_{\text{bias}}(\text{IN})$	$V_i=9$ to 25V , $T_j=25^\circ\text{C}$	—	—	0.8	mA
Load bias current fluctuation	$\Delta I_{\text{bias}}(\text{L})$	$I_o=5$ to 350mA , $T_j=25^\circ\text{C}$	—	—	0.5	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz	—	45	—	μV
Ripple rejection ratio	RR	$V_i=9$ to 19V , $I_o=100\text{mA}$, $f=120\text{Hz}$	59	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF}}(\text{min.})$	$I_o=500\text{mA}$, $T_j=25^\circ\text{C}$	—	2	—	V
Output short circuit current	$I_{\text{O}}(\text{Short})$	$V_i=35\text{V}$, $T_j=25^\circ\text{C}$	—	300	—	mA
Peak output current	$I_{\text{O}}(\text{Peak})$	$T_j=25^\circ\text{C}$	—	700	—	mA
Output voltage temperature coefficient	$\Delta V_o/T_a$	$I_o=5\text{mA}$, $T_j=0$ to 125°C	—	-0.5	—	mV/°C

Note 1) The specified condition $T_j=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_i=11\text{V}$, $I_o=350\text{mA}$, $C_i=0.33\mu\text{F}$ and $C_o=0.1\mu\text{F}$

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

• AN78M07/AN78M07F (7V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_o	$T_j=25^\circ\text{C}$	6.7	7	7.3	V
Output voltage tolerance	V_o	$V_i=9.5$ to 22V , $I_o=5$ to 350mA , $T_j=25^\circ\text{C}$, $P_D \leq *$	6.65	—	7.35	V
Line regulation	REG_{IN}	$V_i=9.5$ to 25V , $T_j=25^\circ\text{C}$	—	6	100	mV
		$V_i=10$ to 25V , $T_j=25^\circ\text{C}$	—	2	50	mV
Load regulation	REG_{L}	$I_o=5$ to 500mA , $T_j=25^\circ\text{C}$	—	20	140	mV
		$I_o=5$ to 200mA , $T_j=25^\circ\text{C}$	—	10	70	mV
Bias current	I_{bias}	$T_j=25^\circ\text{C}$	—	4	6	mA
Input bias current fluctuation	$\Delta I_{\text{bias}}(\text{IN})$	$V_i=10$ to 25V , $T_j=25^\circ\text{C}$	—	—	0.8	mA
Load bias current fluctuation	$\Delta I_{\text{bias}}(\text{L})$	$I_o=5$ to 350mA , $T_j=25^\circ\text{C}$	—	—	0.5	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz	—	48	—	μV
Ripple rejection ratio	RR	$V_i=10$ to 20V , $I_o=100\text{mA}$, $f=120\text{Hz}$	57	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF}}(\text{min.})$	$I_o=500\text{mA}$, $T_j=25^\circ\text{C}$	—	2	—	V
Output short circuit current	$I_{\text{O}}(\text{Short})$	$V_i=35\text{V}$, $T_j=25^\circ\text{C}$	—	300	—	mA
Peak output current	$I_{\text{O}}(\text{Peak})$	$T_j=25^\circ\text{C}$	—	700	—	mA
Output voltage temperature coefficient	$\Delta V_o/T_a$	$I_o=5\text{mA}$, $T_j=0$ to 125°C	—	-0.5	—	mV/°C

Note 1) The specified condition $T_j=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_i=12\text{V}$, $I_o=350\text{mA}$, $C_i=0.33\mu\text{F}$ and $C_o=0.1\mu\text{F}$

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

■ 6932852 0012529 139 ■

Panasonic

■ Electrical Characteristics (Ta=25℃)

• AN78M08/AN78M08F (8V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V _O	T _J =25℃	7.7	8	8.3	V
Output voltage tolerance	V _O	V _I =10.5 to 23V, I _O =5 to 350mA, T _J =25℃, P _D ≤*	7.6	—	8.4	V
Line regulation	REG _{IN}	V _I =10.5 to 25V, T _J =25℃	—	6	100	mV
		V _I =11 to 25V, T _J =25℃	—	2	50	mV
Load regulation	REG _L	I _O =5 to 500mA, T _J =25℃	—	25	160	mV
		I _O =5 to 200mA, T _J =25℃	—	10	80	mV
Bias current	I _{bias}	T _J =25℃	—	4.1	6	mA
Input bias current fluctuation	ΔI _{bias(IN)}	V _I =10.5 to 25V, T _J =25℃	—	—	0.8	mA
Load bias current fluctuation	ΔI _{bias(L)}	I _O =5 to 350mA, T _J =25℃	—	—	0.5	mA
Output noise voltage	V _{no}	f=10Hz to 100kHz	—	52	—	μV
Ripple rejection ratio	RR	V _I =11.5 to 21.5V, I _O =100mA, f=120Hz	56	—	—	dB
Minimum input/output voltage difference	V _{DIF(min.)}	I _O =500mA, T _J =25℃	—	2	—	V
Output short circuit current	I _{O(Short)}	V _I =35V, T _J =25℃	—	300	—	mA
Peak output current	I _{O(Peak)}	T _J =25℃	—	700	—	mA
Output voltage temperature coefficient	ΔV _O /Ta	I _O =5mA, T _J =0 to 125℃	—	-0.5	—	mV/℃

Note 1) The specified condition T_J=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, V_I=14V, I_O=350mA, C_I=0.33 μF and C_O=0.1 μF

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

• AN78M09/AN78M09F (9V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V _O	T _J =25℃	8.65	9	9.35	V
Output voltage tolerance	V _O	V _I =11.5 to 24V, I _O =5 to 350mA, T _J =25℃, P _D ≤*	8.55	—	9.45	V
Line regulation	REG _{IN}	V _I =11.5 to 25V, T _J =25℃	—	7	100	mV
		V _I =12 to 25V, T _J =25℃	—	2	50	mV
Load regulation	REG _L	I _O =5 to 500mA, T _J =25℃	—	25	180	mV
		I _O =5 to 200mA, T _J =25℃	—	10	90	mV
Bias current	I _{bias}	T _J =25℃	—	4.1	6	mA
Input bias current fluctuation	ΔI _{bias(IN)}	V _I =12 to 25V, T _J =25℃	—	—	0.8	mA
Load bias current fluctuation	ΔI _{bias(L)}	I _O =5 to 350mA, T _J =25℃	—	—	0.5	mA
Output noise voltage	V _{no}	f=10Hz to 100kHz	—	60	—	μV
Ripple rejection ratio	RR	V _I =12 to 22V, I _O =100mA, f=120Hz	56	—	—	dB
Minimum input/output voltage difference	V _{DIF(min.)}	I _O =500mA, T _J =25℃	—	2	—	V
Output short circuit current	I _{O(Short)}	V _I =35V, T _J =25℃	—	300	—	mA
Peak output current	I _{O(Peak)}	T _J =25℃	—	700	—	mA
Output voltage temperature coefficient	ΔV _O /Ta	I _O =5mA, T _J =0 to 125℃	—	-0.5	—	mV/℃

Note 1) The specified condition T_J=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, V_I=15V, I_O=350mA, C_I=0.33 μF and C_O=0.1 μF

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

Voltage
Regu-
lators

6932852 0012530 950

Panasonic

■ Electrical Characteristics (Ta=25°C)

• AN78M10/AN78M10F (10V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^\circ\text{C}$	9.6	10	10.4	V
Output voltage tolerance	V_O	$V_I=12.5$ to 25V , $I_O=5$ to 350mA , $T_J=25^\circ\text{C}$, $P_D\leq^*$	9.5	—	10.5	V
Line regulation	REG_{IN}	$V_I=12.5$ to 30V , $T_J=25^\circ\text{C}$	—	7	100	mV
		$V_I=13$ to 25V , $T_J=25^\circ\text{C}$	—	2	50	mV
Load regulation	REG_L	$I_O=5$ to 500mA , $T_J=25^\circ\text{C}$	—	25	200	mV
		$I_O=5$ to 200mA , $T_J=25^\circ\text{C}$	—	10	100	mV
Bias current	I_{bias}	$T_J=25^\circ\text{C}$	—	4.1	6	mA
Input bias current fluctuation	$\Delta I_{\text{bias}}(\text{IN})$	$V_I=13$ to 25V , $T_J=25^\circ\text{C}$	—	—	0.8	mA
Load bias current fluctuation	$\Delta I_{\text{bias}}(\text{L})$	$I_O=5$ to 350mA , $T_J=25^\circ\text{C}$	—	—	0.5	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz	—	65	—	μV
Ripple rejection ratio	RR	$V_I=13$ to 23V , $I_O=100\text{mA}$, $f=120\text{Hz}$	56	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF}}(\text{min.})$	$I_O=500\text{mA}$, $T_J=25^\circ\text{C}$	—	2	—	V
Output short circuit current	$I_{\text{O}}(\text{Short})$	$V_I=35\text{V}$, $T_J=25^\circ\text{C}$	—	300	—	mA
Peak output current	$I_{\text{O}}(\text{Peak})$	$T_J=25^\circ\text{C}$	—	700	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$, $T_J=0$ to 125°C	—	-0.5	—	mV/°C

Note 1) The specified condition $T_J=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=16\text{V}$, $I_O=350\text{mA}$, $C_I=0.33\mu\text{F}$ and $C_O=0.1\mu\text{F}$

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

• AN78M12/AN78M12F (12V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_J=25^\circ\text{C}$	11.5	12	12.5	V
Output voltage tolerance	V_O	$V_I=14.5$ to 27V , $I_O=5$ to 350mA , $T_J=25^\circ\text{C}$, $P_D\leq^*$	11.4	—	12.6	V
Line regulation	REG_{IN}	$V_I=14.5$ to 30V , $T_J=25^\circ\text{C}$	—	8	100	mV
		$V_I=16$ to 30V , $T_J=25^\circ\text{C}$	—	2	50	mV
Load regulation	REG_L	$I_O=5$ to 500mA , $T_J=25^\circ\text{C}$	—	25	240	mV
		$I_O=5$ to 200mA , $T_J=25^\circ\text{C}$	—	10	120	mV
Bias current	I_{bias}	$T_J=25^\circ\text{C}$	—	4.3	6	mA
Input bias current fluctuation	$\Delta I_{\text{bias}}(\text{IN})$	$V_I=14.5$ to 30V , $T_J=25^\circ\text{C}$	—	—	0.8	mA
Load bias current fluctuation	$\Delta I_{\text{bias}}(\text{L})$	$I_O=5$ to 350mA , $T_J=25^\circ\text{C}$	—	—	0.5	mA
Output noise voltage	V_{no}	$f=10\text{Hz}$ to 100kHz	—	75	—	μV
Ripple rejection ratio	RR	$V_I=15$ to 25V , $I_O=100\text{mA}$, $f=120\text{Hz}$	55	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF}}(\text{min.})$	$I_O=500\text{mA}$, $T_J=25^\circ\text{C}$	—	2	—	V
Output short circuit current	$I_{\text{O}}(\text{Short})$	$V_I=35\text{V}$, $T_J=25^\circ\text{C}$	—	300	—	mA
Peak output current	$I_{\text{O}}(\text{Peak})$	$T_J=25^\circ\text{C}$	—	700	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$, $T_J=0$ to 125°C	—	-0.8	—	mV/°C

Note 1) The specified condition $T_J=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=19\text{V}$, $I_O=350\text{mA}$, $C_I=0.33\mu\text{F}$ and $C_O=0.1\mu\text{F}$

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

■ 6932852 0012531 897 ■

Panasonic

■ Electrical Characteristics (Ta=25℃)

• AN78M15/AN78M15F (15V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V _O	T _J =25℃	14.4	15	15.6	V
Output voltage tolerance	V _O	V _I =17.5 to 30V, I _O =5 to 350mA, T _J =25℃, P _D ≤*	14.25	—	15.75	V
Line regulation	REG _{IN}	V _I =17.5 to 30V, T _J =25℃	—	10	100	mV
		V _I =20 to 30V, T _J =25℃	—	3	50	mV
Load regulation	REG _L	I _O =5 to 500mA, T _J =25℃	—	25	300	mV
		I _O =5 to 200mA, T _J =25℃	—	10	150	mV
Bias current	I _{bias}	T _J =25℃	—	4.3	6	mA
Input bias current fluctuation	ΔI _{bias} (IN)	V _I =17.5 to 30V, T _J =25℃	—	—	0.8	mA
Load bias current fluctuation	ΔI _{bias} (L)	I _O =5 to 350mA, T _J =25℃	—	—	0.5	mA
Output noise voltage	V _{no}	f=10Hz to 100kHz	—	90	—	μV
Ripple rejection ratio	RR	V _I =18.5 to 28.5V, I _O =100mA, f=120Hz	54	—	—	dB
Minimum input/output voltage difference	V _{DIF(min.)}	I _O =500mA, T _J =25℃	—	2	—	V
Output short circuit current	I _{O(Short)}	V _I =35V, T _J =25℃	—	300	—	mA
Peak output current	I _{O(Peak)}	T _J =25℃	—	700	—	mA
Output voltage temperature coefficient	ΔV _O /Ta	I _O =5mA, T _J =0 to 125℃	—	-1	—	mV/℃

Note 1) The specified condition T_J=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, V_I=23V, I_O=350mA, C_I=0.33 μF and C_O=0.1 μF

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

• AN78M18/AN78M18F (18V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V _O	T _J =25℃	17.3	18	18.7	V
Output voltage tolerance	V _O	V _I =21 to 33V, I _O =5 to 350mA, T _J =25℃, P _D ≤*	17.1	—	18.9	V
Line regulation	REG _{IN}	V _I =21 to 33V, T _J =25℃	—	10	100	mV
		V _I =22 to 33V, T _J =25℃	—	5	50	mV
Load regulation	REG _L	I _O =5 to 500mA, T _J =25℃	—	30	360	mV
		I _O =5 to 200mA, T _J =25℃	—	10	180	mV
Bias current	I _{bias}	T _J =25℃	—	4.4	6	mA
Input bias current fluctuation	ΔI _{bias} (IN)	V _I =21 to 33V, T _J =25℃	—	—	0.8	mA
Load bias current fluctuation	ΔI _{bias} (L)	I _O =5 to 350mA, T _J =25℃	—	—	0.5	mA
Output noise voltage	V _{no}	f=10Hz to 100kHz	—	100	—	μV
Ripple rejection ratio	RR	V _I =22 to 32V, I _O =100mA, f=120Hz	53	—	—	dB
Minimum input/output voltage difference	V _{DIF(min.)}	I _O =500mA, T _J =25℃	—	2	—	V
Output short circuit current	I _{O(Short)}	V _I =35V, T _J =25℃	—	300	—	mA
Peak output current	I _{O(Peak)}	T _J =25℃	—	700	—	mA
Output voltage temperature coefficient	ΔV _O /Ta	I _O =5mA, T _J =0 to 125℃	—	-1.0	—	mV/℃

Note 1) The specified condition T_J=25℃ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, V_I=27V, I_O=350mA, C_I=0.33 μF and C_O=0.1 μF

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

Voltage
Regu-
lators

6932852 0012532 723

Panasonic

■ Electrical Characteristics (Ta=25°C)

• AN78M20/AN78M20F (20V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_j=25^\circ\text{C}$	19.2	20	20.8	V
Output voltage tolerance	V_O	$V_I=23\text{ to }35\text{V}$, $I_O=5\text{ to }350\text{mA}$, $T_j=25^\circ\text{C}$, $P_D\leq^*$	19	—	21	V
Line regulation	REG_{IN}	$V_I=23\text{ to }35\text{V}$, $T_j=25^\circ\text{C}$	—	10	100	mV
		$V_I=24\text{ to }35\text{V}$, $T_j=25^\circ\text{C}$	—	5	50	mV
Load regulation	REG_L	$I_O=5\text{ to }500\text{mA}$, $T_j=25^\circ\text{C}$	—	30	400	mV
		$I_O=5\text{ to }200\text{mA}$, $T_j=25^\circ\text{C}$	—	10	200	mV
Bias current	I_{bias}	$T_j=25^\circ\text{C}$	—	4.4	6	mA
Input bias current fluctuation	$\Delta I_{\text{bias}}(\text{IN})$	$V_I=23\text{ to }35\text{V}$, $T_j=25^\circ\text{C}$	—	—	0.8	mA
Load bias current fluctuation	$\Delta I_{\text{bias}}(\text{L})$	$I_O=5\text{ to }350\text{mA}$, $T_j=25^\circ\text{C}$	—	—	0.5	mA
Output noise voltage	V_{no}	$f=10\text{Hz to }100\text{kHz}$	—	110	—	μV
Ripple rejection ratio	RR	$V_I=24\text{ to }34\text{V}$, $I_O=100\text{mA}$, $f=120\text{Hz}$	53	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF}}(\text{min.})$	$I_O=500\text{mA}$, $T_j=25^\circ\text{C}$	—	2	—	V
Output short circuit current	$I_{\text{O}}(\text{Short})$	$V_I=35\text{V}$, $T_j=25^\circ\text{C}$	—	300	—	mA
Peak output current	$I_{\text{O}}(\text{Peak})$	$T_j=25^\circ\text{C}$	—	700	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$, $T_j=0\text{ to }125^\circ\text{C}$	—	-1.0	—	mV/°C

Note 1) The specified condition $T_j=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

Note 2) When not specified, $V_I=29\text{V}$, $I_O=350\text{mA}$, $C_I=0.33\mu\text{F}$ and $C_O=0.1\mu\text{F}$

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

• AN78M24/AN78M24F (24V Type)

Parameter	Symbol	Condition	min	typ	max	Unit
Output voltage	V_O	$T_j=25^\circ\text{C}$	23	24	25	V
Output voltage tolerance	V_O	$V_I=27\text{ to }38\text{V}$, $I_O=5\text{ to }350\text{mA}$, $T_j=25^\circ\text{C}$, $P_D\leq^*$	22.8	—	25.2	V
Line regulation	REG_{IN}	$V_I=27\text{ to }38\text{V}$, $T_j=25^\circ\text{C}$	—	10	100	mV
		$V_I=28\text{ to }38\text{V}$, $T_j=25^\circ\text{C}$	—	5	50	mV
Load regulation	REG_L	$I_O=5\text{ to }500\text{mA}$, $T_j=25^\circ\text{C}$	—	30	480	mV
		$I_O=5\text{ to }200\text{mA}$, $T_j=25^\circ\text{C}$	—	10	240	mV
Bias current	I_{bias}	$T_j=25^\circ\text{C}$	—	4.5	6	mA
Input bias current fluctuation	$\Delta I_{\text{bias}}(\text{IN})$	$V_I=27\text{ to }38\text{V}$, $T_j=25^\circ\text{C}$	—	—	0.8	mA
Load bias current fluctuation	$\Delta I_{\text{bias}}(\text{L})$	$I_O=5\text{ to }350\text{mA}$, $T_j=25^\circ\text{C}$	—	—	0.5	mA
Output noise voltage	V_{no}	$f=10\text{Hz to }100\text{kHz}$	—	170	—	μV
Ripple rejection ratio	RR	$V_I=28\text{ to }38\text{V}$, $I_O=100\text{mA}$, $f=120\text{Hz}$	50	—	—	dB
Minimum input/output voltage difference	$V_{\text{DIF}}(\text{min.})$	$I_O=500\text{mA}$, $T_j=25^\circ\text{C}$	—	2	—	V
Output short circuit current	$I_{\text{O}}(\text{Short})$	$V_I=35\text{V}$, $T_j=25^\circ\text{C}$	—	300	—	mA
Peak output current	$I_{\text{O}}(\text{Peak})$	$T_j=25^\circ\text{C}$	—	700	—	mA
Output voltage temperature coefficient	$\Delta V_O/T_a$	$I_O=5\text{mA}$, $T_j=0\text{ to }125^\circ\text{C}$	—	-1.2	—	mV/°C

Note 1) The specified condition $T_j=25^\circ\text{C}$ means that the test should be carried out with the test time so short (within 10ms) that the drift in characteristic value due to the rise in chip junction temperature can be ignored.

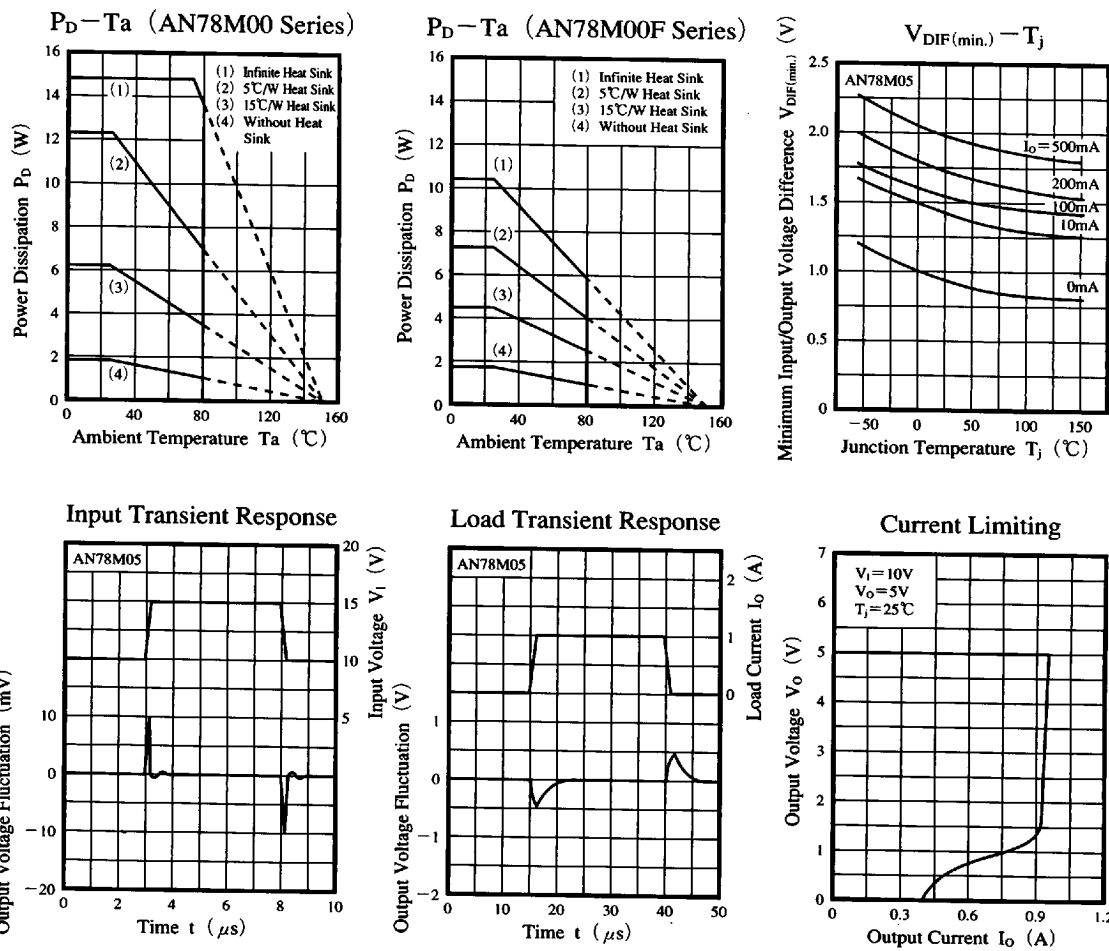
Note 2) When not specified, $V_I=33\text{V}$, $I_O=350\text{mA}$, $C_I=0.33\mu\text{F}$ and $C_O=0.1\mu\text{F}$

* AN78M00 Series : 15W, AN78M00F Series : 10.25W

■ 6932852 0012533 66T ■

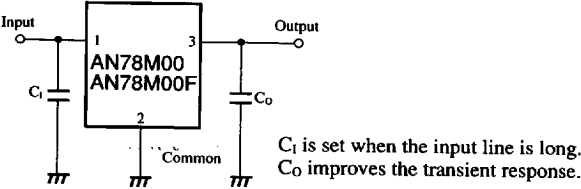
Panasonic

■ Characteristics Curve



Voltage
Regu-
lators

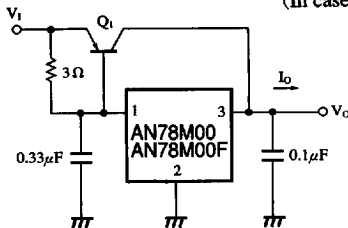
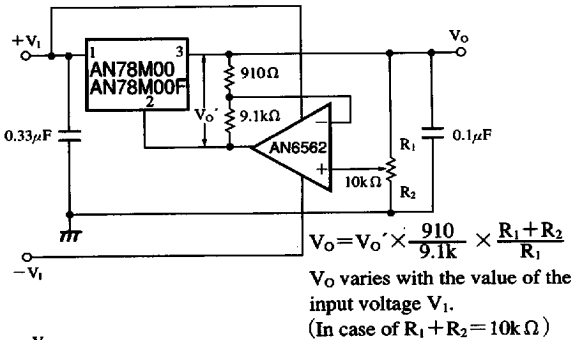
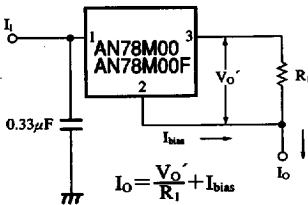
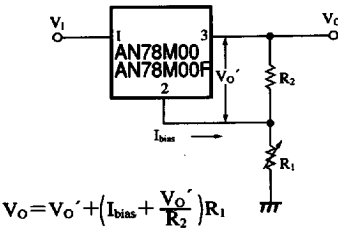
■ Basic Regulator Circuit



6932852 0012534 5T6

Panasonic

■ Application Circuits



■ 6932852 0012535 432 ■

Panasonic